

Characterization of Inverse-Gaussian and Gamma Distributions Through Their Length-Biased Distributions

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Key Words — Length biased distribution, Weighted distribution, Inverse Gaussian distribution, Gamma distribution

Reader Aids —

Purpose: Widen state of the art

Special math needed for explanations: Probability

Special math needed to use results: Same

Results useful to: Reliability theoreticians

Abstract — Let Y be a length-biased random variable corresponding to a random variable X having an inverse-Gaussian or Gamma distribution. It is shown that Y can be written as a linear combination of X and a chi-square random variable and conversely X can be characterized through this relationship. Finally the Wald distribution is characterized.

1. INTRODUCTION

Let X be a non-negative random variable having an absolutely continuous pdf $f(\cdot)$. Let X have a finite first moment, say μ ; one can define another pdf $h(\cdot)$ as:

$$h(x) = \frac{xf(x)}{\mu}, \quad x > 0 \quad (1.1)$$

The random variable Y with pdf $h(\cdot)$ is known as the length-biased random variable associated with X . The random variable Y occurs in the studies of lifetime models [1, 2]. Cox [3, page 65] provides the following interpretation of pdf $h(\cdot)$: Consider a sample of failure times with pdf $f(x)$ and let the probability of selecting any individual unit in the population be proportional to its size or length x . Then the failure time selected has the pdf $h(x)$. Also, length-biased distributions arise in various probability-proportional-to-size (pps) sampling procedures [7]. In fact $h(\cdot)$ is simply a special weighted distribution with weight x [5, 6].

This note presents a result characterizing the inverse Gaussian and Gamma distributions. These are common probability distributions in reliability and lifetime models. Finally a characterization of Wald distribution, which is a special case of inverse Gaussian, is given.

2. THE MAIN RESULT

The theorem consists of two characterizations of similar nature and we state these in the following:

Theorem 2.1 Let X be a non-negative random variable with pdf $f(\cdot)$, characteristic function $\phi(\cdot)$ and mean μ . Let Y be the random variable with pdf $h(\cdot)$ as defined in (1.1). If Y can be written as $Y \stackrel{d}{=} X + Z/\lambda$ where $\lambda > 0$ and Z is a chi square random variable, s -independent of X with,

- i. a single degree of freedom then X has an inverse gaussian distribution with shape parameter $\lambda\mu^2$ and mean μ respectively.
- ii. two degrees of freedom then X has a gamma distribution with shape and scale parameters $\alpha = \lambda\mu/2$ and $\beta = 2/\lambda$.

Proof. Let $\psi(t)$ be the characteristic function of $Y \stackrel{d}{=} X + Z/\lambda$, $\lambda > 0$. To prove i, we observe that under the assumptions stated in the theorem and using (1.1),

$$\psi(t) = (i\mu)^{-1} \phi'(t) = \phi(t) \left(1 - \frac{2it}{\lambda}\right)^{-1/2} \quad (2.1)$$

$$\phi'(t) \equiv \frac{\partial}{\partial t} \phi(t).$$

Solve (2.1) and use the fact that $\phi(0) = 1$:

$$\phi(t) = \exp[\lambda\mu(1 - (1 - 2it/\lambda)^{1/2})]. \quad (2.2)$$

Eq (2.2) after appropriate parameterization, is easily seen to be the characteristic function of an inverse Gaussian r.v. When $\mu = 1$, eq (2.2) reduces to the characterization of a Wald distribution [1].

The proof of ii is similar and thus we skip it. As a corollary, the length-biased distribution of a χ_n^2 is χ_{n+2}^2 . *Q.E.D.*

3. A CHARACTERIZATION OF WALD DISTRIBUTION

In [1], a characterization of the Wald distribution was given. Motivated by [4, lemma 6.1.3], another characterization is given in theorem 3.1.

Theorem 3.1 Let $F(\cdot)$ be the Cdf of a non-negative random variable Y . Let $E(Y^{-1})$ exist, and let the relation

$$\int y^{-1} \exp(ity) dF(y) = \left(1 - \frac{2it}{\lambda}\right)^{1/2} \int \exp(ity) dF(y)$$

be valid for some $\lambda > 0$ and for all $|t| < \delta$ for some δ , then Y has the length-biased distribution associated with a Wald random variable, with parameter λ (or equivalently Y^{-1} has a Wald distribution).

Proof: Let

$$A(t) = \int_0^{\infty} y^{-1} \exp(ity) dF(y)$$

and

$$\phi(t) = \int_0^{\infty} \exp(ity) dF(y).$$

Thus

$$A'(t) = \frac{\partial A(t)}{\partial t} = i\phi(t)$$

and

$$\frac{A'(t)}{A(t)} = i \left(1 - \frac{2it}{\lambda}\right)^{-1/2} \quad (3.1)$$

Solution of differential equation in (3.1) is

$$A(t) = C e^{-\lambda} \left(1 - \frac{2it}{\lambda}\right)^{1/2}$$

for some constant C and thus using the fact that $\phi(0) = 1$, we have

$$\phi(t) = \left(1 - \frac{2it}{\lambda}\right)^{-1/2} \exp\left(\lambda \left[1 - \left(1 - \frac{2it}{\lambda}\right)^{1/2}\right]\right). \quad (3.2)$$

The r.h.s. of (3.2) is the characteristic function of the length-biased distribution associated with a Wald distribution. That Y^{-1} has a Wald distribution follows from [1].

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Manuscript TR88-074 received 1988 March 22; revised 1989 March 27; revised 1989 August 2.

IEEE Log Number 32033

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